

Examinator-Pro offers product and test engineers everything they need to characterize new ICs and test programs, quickly ramp up production at OSATs and identify and diagnose yield excursions when they occur. Examinator-Pro converts standard test data files such as STDF, PCM and any of 120 other formats into comprehensive reports and insightful interactive analysis.

Examinator-Pro is incredibly easy to use, fast, and requires no special training. Simply download the free trial version and be up and running, analyzing your test data in minutes. The majority of our 8500+ users are product, test, and process engineers from fabless, IDM, OSAT, and ATE companies. Engineers choose Examinator-Pro because it allows them to aggregate and analyze different kinds of test data quickly and reliably (Fab, bench, ATE, etc.) Thousands of users attest to the value of Examinator-Pro in helping get jobs done faster, allowing more time for high-value activities.

Whether at a pre-revenue startup with one engineer, a global company with thousands of them, or anywhere in between, Galaxy's software scales seamlessly from a few wafers to hundreds even thousands per day. Since Examinator-Pro acts as a common user interface for all Galaxy products, using it helps prepare users for growing into an automated yield management system such as Galaxy's Yield-Man and our automated outlier removal system PAT-Man.

For more than 25 years Galaxy Semiconductor is the trusted solution for enhancing yields, reducing defects per million (DPM), and optimizing semiconductor manufacturing processes. Galaxy's experienced team provides powerful, scalable, and easy to use intelligent data analytics while providing first class support.

FEATURES AND BENEFITS

- GLOBAL INFORMATION: Tester, lot, operator information
- YIELD INFORMATION: Good parts, failing parts, parts re-tested
- TEST SUMMARY: Cp, Cpk, mean, sigma, skew fail count, etc.
- HISTOGRAMS, TREND GRAPHS,
 PROBABILITY PLOTS: Quickly view &
 understand the test distribution
- PARAMETRIC TEST WAFER MAP:
 Analyze the test gradient on your wafer
 to investigate process problems
- WAFER MAP: See bins, or parametric values for each x,y coordinate
- WAFER STACKING: Stack wafers to see systematic geographical wafer issues
- FLEXIBLE INPUT FORMAT: Supports 120+ different tester platforms and data formats, including STDF, GDF, ATDF, WAT, PCM, and CSV
- PARSING WIZARD: Import custom data (csv, txt) without any custom parsers or development
- PARAMETRIC TREND CHARTS: See how test results evolve over time in production
- PARETO REPORTS: Cpk of tests, failures, binning
- TESTER & BOARD QUALIFICATION:
 Conduct gage R&R studies
- REDUCE TEST TIME: Pearson's
 Correlation Report displays highest
 correlated tests
- RELIABILITY AND SHIFT ANALYSIS: Measure parametric shifts based on time and temperature
- VIRTUAL RE-TEST: Analyze the yield impact of loosening or tightening test
 limits.
- CORRELATION REPORTS: Align any tests and see the R-Squared Value
- MULTI-SITE ANALYSIS: Quickly compare and overlay all test sites

